Search Notes



Application/Control No.	Applicant(s)/Patent under Reexamination	
10/606,487	GEE ET AL.	
Examiner	Art Unit	
Anthony Fick	1753	

	SEARCHED		
Class	Subclass	Date	Examiner
136	252, 256	9/12/2006	ADF
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
136	252, 256	9/12/2006	ADF		
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SEARCH NO' (INCLUDING SEARCH)
·	DATE	EXMR
See EAST search history	9/12/2006	ADF
Inventor search	9/7/2006	ADF
Consulted with Jeffrey Barton and Nam Nguyen	9/11/2006	ADF
Internet database search, IEEE and Google scholar, for inventors and keywords	9/8/2006	ADF
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